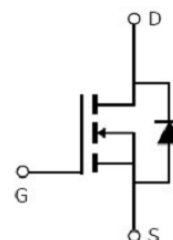


**Main Product Characteristics:**

$V_{DSS}$	800V
$R_{DS(on)}$	13Ω (typ.)
$I_D$	1A


**SOT223**

**Marking and pin Assignment**

**Schematic diagram**
**Features and Benefits:**

- Advanced MOSFET process technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 150°C operating temperature


**Description:**

It utilizes the latest processing techniques to achieve the high cell density and reduces the on-resistance with high repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in power switching application and a wide variety of other applications.

**Absolute max Rating:**

Symbol	Parameter	Max.	Units
$I_D @ TC = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ ①	1	A
$I_D @ TC = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$ ①	0.65	
$I_{DM}$	Pulsed Drain Current②	4	
$P_D @ TC = 25^\circ C$	Power Dissipation③	40	W
	Linear Derating Factor	0.32	W/°C
$V_{DS}$	Drain-Source Voltage	800	V
$V_{GS}$	Gate-to-Source Voltage	± 30	V
$E_{AS}$	Single Pulse Avalanche Energy @ L=100mH	50	mJ
$I_{AS}$	Avalanche Current @ L=100mH	1	A
$T_J T_{STG}$	Operating Junction and Storage Temperature Range	-55 to + 150	°C

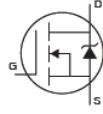
## Thermal Resistance

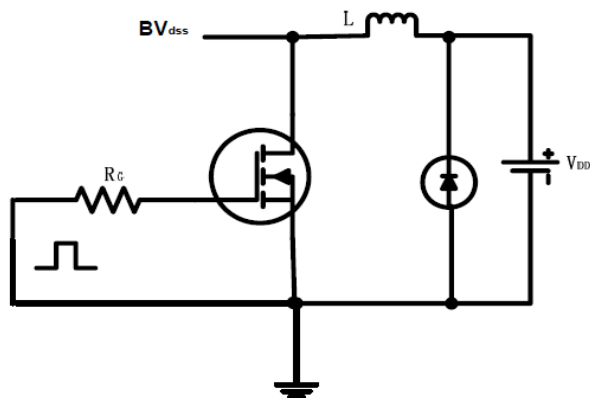
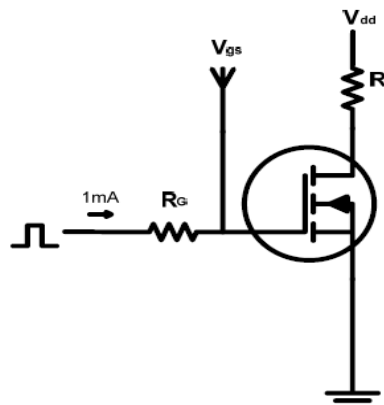
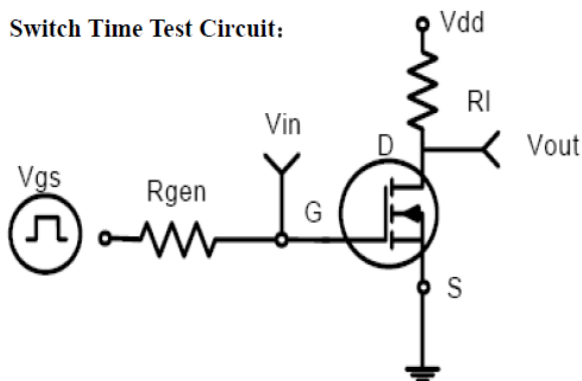
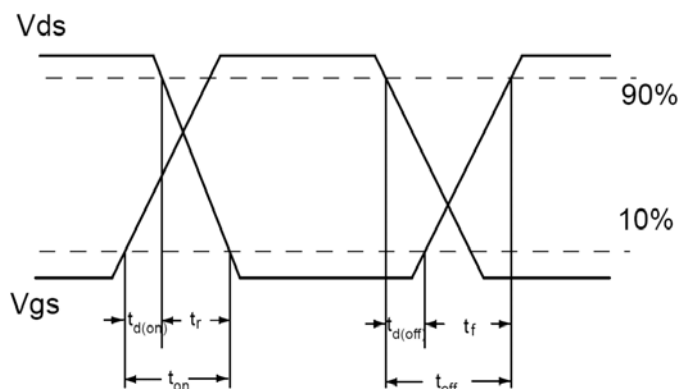
Symbol	Characterizes	Typ.	Max.	Units
R <sub>θJC</sub>	Junction-to-case <sup>③</sup>	—	2.88	°C/W
R <sub>θJA</sub>	Junction-to-ambient (t ≤ 10s) <sup>④</sup>	—	62	°C/W
	Junction-to-Ambient (PCB mounted, steady-state) <sup>④</sup>	—	40	°C/W

## Electrical Characterizes @T<sub>A</sub>=25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source breakdown voltage	800	—	—	V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
R <sub>DS(on)</sub>	Static Drain-to-Source on-resistance	—	13	16	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> = 0.5A T <sub>J</sub> = 125°C
		—	18	—		
V <sub>GS(th)</sub>	Gate threshold voltage	2	—	4	V	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA T <sub>J</sub> = 125°C
		—	2.0	—		
I <sub>DSS</sub>	Drain-to-Source leakage current	—	—	1	μA	V <sub>DS</sub> = 800V, V <sub>GS</sub> = 0V T <sub>J</sub> = 125°C
		—	—	50		
I <sub>GSS</sub>	Gate-to-Source forward leakage	—	—	100	nA	V <sub>GS</sub> = 30V V <sub>GS</sub> = -30V
		—	—	-100		
Q <sub>g</sub>	Total gate charge	—	8.9	—	nC	I <sub>D</sub> = 1A, V <sub>DS</sub> =640V, V <sub>GS</sub> = 10V
Q <sub>gs</sub>	Gate-to-Source charge	—	2.1	—		
Q <sub>gd</sub>	Gate-to-Drain("Miller") charge	—	3.3	—		
t <sub>d(on)</sub>	Turn-on delay time	—	8.1	—	ns	V <sub>GS</sub> =10V, V <sub>DS</sub> =400V, R <sub>L</sub> =44Ω, R <sub>GEN</sub> =25Ω I <sub>D</sub> =1A
t <sub>r</sub>	Rise time	—	29	—		
t <sub>d(off)</sub>	Turn-Off delay time	—	19	—		
t <sub>f</sub>	Fall time	—	40	—		
C <sub>iss</sub>	Input capacitance	—	220	—	pF	V <sub>GS</sub> = 0V V <sub>DS</sub> = 25V f = 1MHz
C <sub>oss</sub>	Output capacitance	—	15	—		
C <sub>rss</sub>	Reverse transfer capacitance	—	2	—		

## Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	1	A	MOSFET symbol showing the integral reverse p-n junction diode. 
I <sub>SM</sub>	Pulsed Source Current (Body Diode)	—	—	4	A	
V <sub>SD</sub>	Diode Forward Voltage	—	1.2	1.5	V	I <sub>S</sub> =1A, V <sub>GS</sub> =0V
t <sub>rr</sub>	Reverse Recovery Time	—	362	—	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 1A,
Q <sub>rr</sub>	Reverse Recovery Charge	—	798	—	nC	di/dt = 100A/μs

**Test circuits and Waveforms**
**EAS test circuits:**

**Gate charge test circuit:**

**Switch Time Test Circuit:**

**Switch Waveforms:**

**Notes:**

- ① The maximum current rating is limited by bond-wires.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of  $R_{\theta JA}$  is measured with the device mounted on 1in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ C$

Typical electrical and thermal characteristics

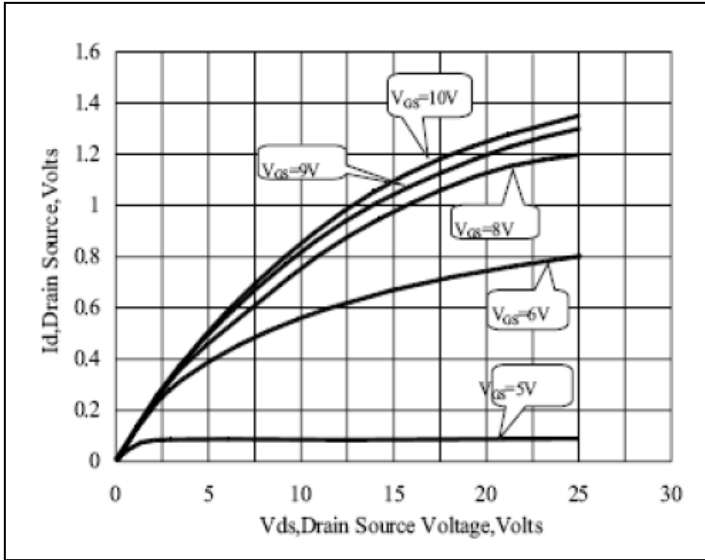


Figure 1: Typical Output Characteristics

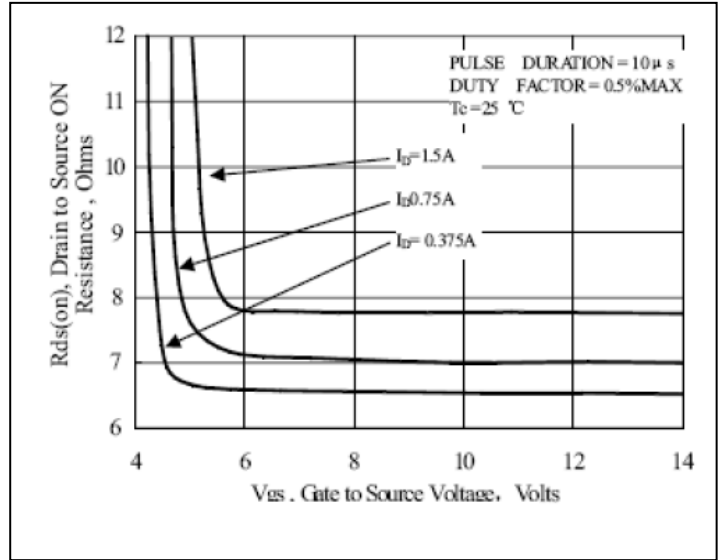


Figure 2. On-Resistance Vs. gate to source voltage

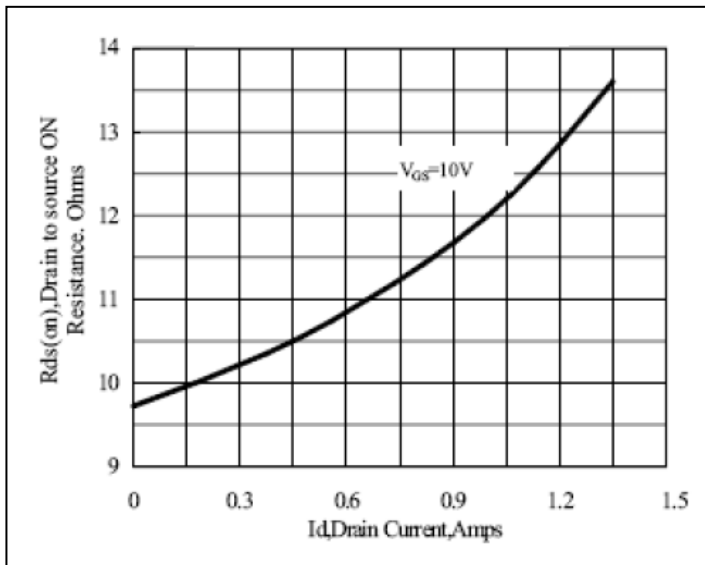


Figure 3. On-Resistance Vs. Drain to Source Current

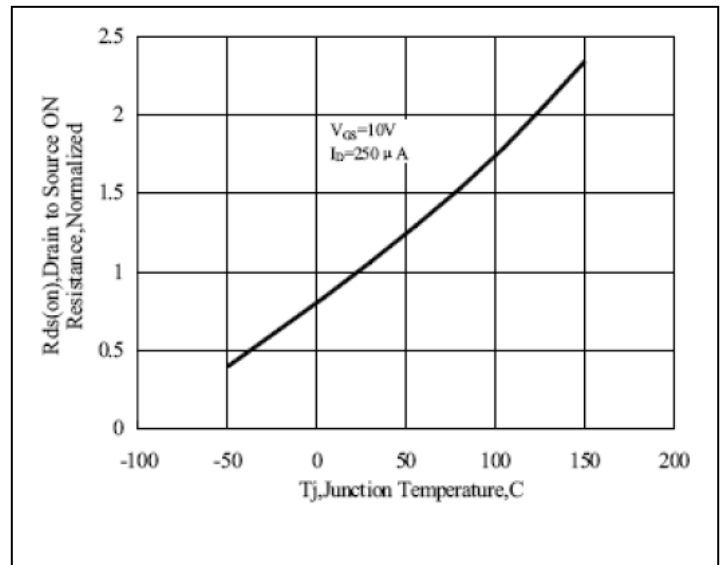
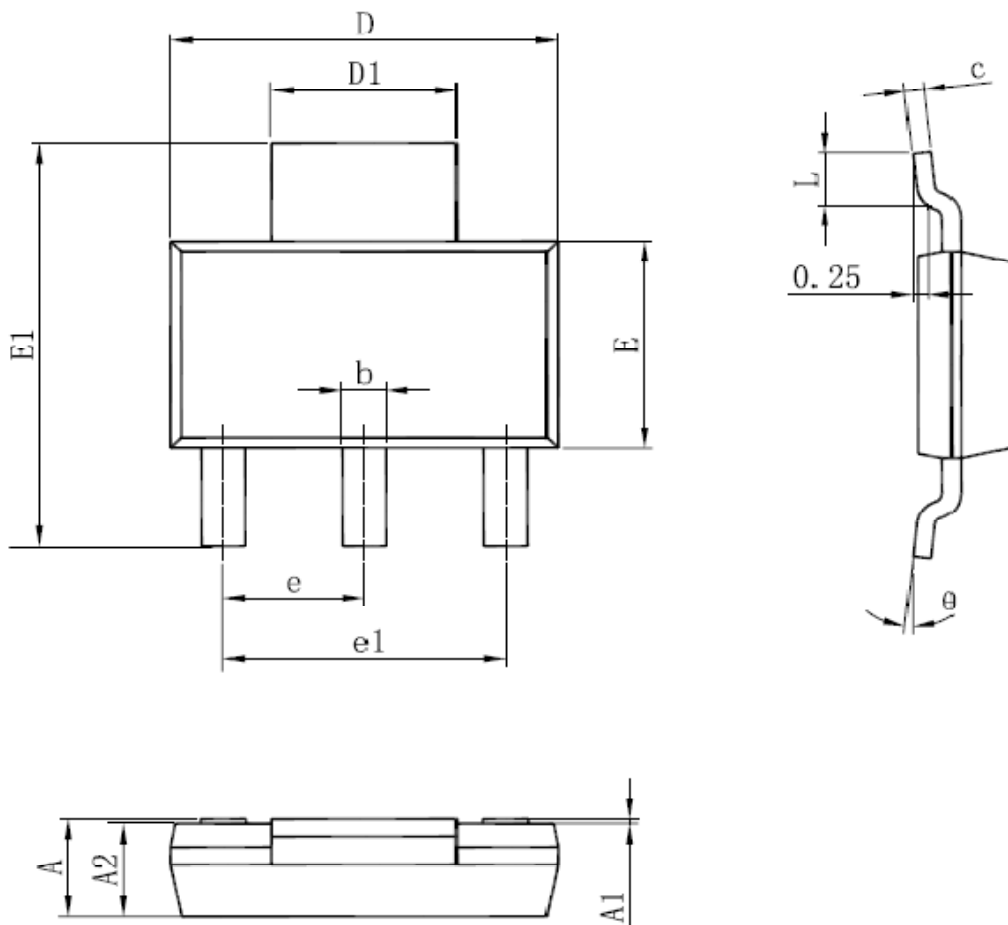


Figure 4: Normalized On-Resistance Vs. Case Temperature

**Mechanical Data(SOT223):**


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.520	1.800	0.060	0.071
A1	0.000	0.100	0.000	0.004
A2	1.500	1.700	0.059	0.067
b	0.660	0.820	0.026	0.032
c	0.250	0.350	0.010	0.014
D	6.200	6.400	0.244	0.252
D1	2.900	3.100	0.114	0.122
E	3.300	3.700	0.130	0.146
E1	6.830	7.070	0.269	0.278
e	2.300(BSC)		0.091(BSC)	
e1	4.500	4.700	0.177	0.185
L	0.900	1.150	0.035	0.045
θ	0°	10°	0°	10°

**Ordering and Marking Information**
**Device Marking: 1N80G5**

**Package (Available)**  
**SOT-223**  
**Operating Temperature Range**  
**C : -55 to 150 °C**

**Devices per Unit:**

Package Type	Units/Tube	Tubes/Inner Box	Units/Inner Box	Inner Boxes/ Carton Box	Units/ Carton Box
SOT223	3000	10	30000	4	120000

**Reliability Test Program**

Test Item	Conditions	Duration	Sample Size
High Temperature Reverse Bias(HTRB)	T <sub>j</sub> =125°C to 150°C @ 80% of Max V <sub>DSS</sub> /V <sub>CES</sub> /V <sub>R</sub>	168 hours 500 hours 1000 hours	3 lots x 77 devices
High Temperature Gate Bias(HTGB)	T <sub>j</sub> =150°C @ 100% of Max V <sub>GSS</sub>	168 hours 500 hours 1000 hours	3 lots x 77 devices

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